

PATENT
DOCKET NO.: 1834-2

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANT : Kim et al.
SERIAL NO. : not yet assigned
FILED : simultaneously herewith
TITLE : APPARATUS AND METHOD FOR MEASUREMENT OF FILM
THICKNESS USING IMPROVED FAST FOURIER
TRANSFORMATION

PRELIMINARY AMENDMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

Preliminary to the initial Office Action, please amend the above-identified
application as follows: